



TECHNISCHE
UNIVERSITÄT
WIEN

INSTITUT FÜR
ANGEWANDTE PHYSIK
Institute of Applied Physics
vormals/formerly
Institut für Allgemeine Physik



Wiedner Hauptstraße 8-10/E134, 1040 Wien/Vienna, Austria – Tel: +43 1 58801 13401 / Fax: +43 1 58801 13499 – E-mail: office@iap.tuwien.ac.at / <http://www.iap.tuwien.ac.at>

IAP-SEMINAR

ANNOUNCEMENT

- Date:** Tuesday, 29.11.2016
Time: 16:00 s.t.
Location: Technische Universität Wien, Institut für Angewandte Physik, E134
yellow tower „B“, 5th floor, Sem.R. DB gelb 05 B (room number
DB05L03), 1040 Wien, Wiedner Hauptstraße 8-10
- Lecturer:** Dr. Luděk Frank
Institute of Scientific Instruments, The Czech Academy of Sciences,
Brno/CZ
- Subject:** Very Low Energy Scanning Electron Microscopy
- Abstract:** The seminar lecture will introduce the scanning electron microscopy with the biased specimen that enable arbitrary variations of the landing energy of electrons at consistent quality of images. Fundamental electron-optical features of this configuration will be described together with appropriate detection strategies, examples of proven detectors and other required features of the device. Results of demonstration experiments will be presented for imaging in reflected as well as transmitted electrons throughout the entire energy scale. Application examples concerning important families of samples will include metallic and non-metallic materials and semiconductors as well as sections of biological tissues. Treatment of surfaces with slow electrons will be also discussed.

*All interested colleagues are welcome to this seminar lecture
(45 minutes presentation followed by discussion).*

*W. Werner e.h.
(Seminar-Chairperson)*

*F. Aumayr e.h.
(LVA-Leiter)*